

ABSTRACT OF THE DISCLOSURE

5 The present invention is drawn to methods for sampling and/or testing for the presence of whisker-like metallic particulates in data centers or computer rooms. For example, a method for discovering the presence of an undesired whisker-like metallic particulate in a data center is disclosed comprising providing a tool having a conductive adhesive portion wherein the conductive adhesive portion is capable of capturing and retaining the whisker-like metallic particulates in their fragile condition, locating a surface of the data center where
10 metallic particulates may be present, extracting from the surface any whisker-like metallic particulates present in substantially their fragile condition using the tool, and confirming with an electron microscope whether or not any whisker-like metallic particulates are present on the conductive adhesive portion of the tool.

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